PAUL SCHERRER INSTITUT



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OMNY – an instrument for high-resolution multi-keV X-ray tomography



Traditional (x-ray, bright field) microscopy



Object is directly imaged to a 2D detector.

Resolution depends on imaging optics, limiting factor especially at hard X-rays

Low efficiency of X-ray optics (Fresnel zone plate approx. 10%) \rightarrow increased dose







Combining coherent diffractive imaging with STXM





overlapping illumination \rightarrow shared information \rightarrow can be analyzed by iterative phase retrieval algorithms

Thibault P., et al., SCIENCE 321, 379 (2008).





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- + Resolution not determined by spot size of the X-rays
- + Suitable to hard X-rays (multi keV) \rightarrow thick samples
- + Lens-less no imaging optics between sample and detector
 - ightarrow dose efficient, resolution not limited by optics
- + Phase and absorption contrast
- + Quantitative: imaging the electron density
- Data analysis is involved
- Resolution depends on sample positioning accuracy ightarrow involved instrumentation
- Coherent illumination of the sample needed!



Access 3D information via
computed tomography
→ obtain many projections of the sample at different angle of incidence.





OMNY – tOMography Nano crYo endstation

Goal: Development of a **dedicated instrument** to perform tomography at the **nano-scale** on **biological samples** and condensed matter physics samples using Ptychography in a **controlled sample environment**.

- Nano positioning of the sample
- Rotation of the sample for tomography (vertical axis)
- Beam conditioning: Fresnel Zone-plate illumination
- ➤Cryogenic temperatures
- ➤UHV environment
- Sample transfer of frozen bio-samples (contamination free)



Resolution goal: 10 nm in 3D

ightarrow aiming at positioning accuracy of sub 10 nm

(sample versus beam = sample versus X-ray lens)



Metrology for OMNY

Accurate sample positioning
→ measure relative position FZP vs. sample

vertical rotation axis

→ for vertical measurement a plane mirror can be used





Heterodyne laser interferometry

- Resolution: 0.3 nm
- non-contact, long range
- exteroceptive: include thermal drifts in the measurement
- linear, accurate and stable scale



Metrology for OMNY

vertical rotation axis

→ for horizontal measurement a spherical mirror is used (equator of a sphere)

BUT

→ no centering mechanics between mirror and sample → wobble of sphere → beam loss







Metrology for OMNY: Tracking interferometer

Position sensitive detector measures sphere motion perpendicular to laser beam propagation.

Closed loop: interferometer tracks the reference sphere and keeps pointing a its center







Compensation of mechanical tracking error motion needed – details in M. Holler and J. Raabe, Opt. Eng. 54(5) 054101 (2015)

Pat. publication no. WO 2012079875 A1



Two instruments with different sample environements

metrology system \blacksquare

- fIOMNI (flexible tOMography Nano Imaging)
- + nano-positioning, tomography with interferometer
- + no cryogenic sample environment
 - \rightarrow limited to radiation hard samples
- + atmospheric pressure
- + breadboard style flexible sample environments

OMNY (tOMography Nano crYo)

- + optimized mechanical structures
- + cryogenic environment and UHV





M. Holler, et al., Rev. Sci. Instrum. 83, 073703 (2012)



fIOMNI (flexible tOMography Nano Imaging)





fIOMNI (flexible tOMography Nano Imaging)



Sample on reference mirror

X-ray

fluorescence

microscope

for finding

sample

(horizontal)





fIOMNI Resolution Test in 3D

3D Test sample: Nanoporous glass ERM®-FD122, Mean pore width 140 nm, ALD coated (Ta₂O₅) 37 nm **3D resolution: 16 nm** (Fourier shell correlation), 720 projections, voxel size: 10 nm³



Innovation Award on Synchrotron Radiation 2014 for high-resolution 3D hard X-ray microscopy

Scientific Reports 4, 3857 (2014)



Example: Fluid Cracking Catalyst

- characterization of interparticle pores at micro- and nanometer-length scales
- visualize and identify individual components in pre-shaped catalyst bodies used in fluid catalytic cracking.





SEM images

FIB sample prep



TOMCAT

Full-field, voxel size 0.3 microns Resolution 0.7 microns FOV 850x700 microns²



J. C. da Silva, *et al.*, ChemCatChem, 7, 413-416 (2015)



3 D rendering of the pores in light blue, the zeolite type Y in blue, and the metakaolin clay in red.



419 diffraction patterns per projection 450 projections



CAD rendering of cryogenic OMNY



Details of this instrument and new measurement results will be presented only and are not available in this reduced version of the talk!



View into the chamber



Details of this instrument and new measurement results will be presented only and are not available in this reduced version of the talk!